Se	arc	:h	No	ote	S	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/822,898	CLAY ET AL.	
Examiner	Art Unit	
Ba Huynh	2179	

	SEARCHED			
Class	Subclass	Date	Examiner	
715	810	11/17/2005	НВ	
	817			
	818			
	815			
	821			
	830			

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
	<u> </u>	,		

SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
East: USpat, USpgpub, Epo, Jpo, Derwent, IBM-tdb files searched.	11/17/2005	НВ
		-